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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In the Application of: PATON

Serial No.: 09/680,286

Filing Date: April 6, 2000

Title: REMOTE MONITORING OF CRITICAL PARAMETERS FOR CALIBRATION
OF MANUFACTURING EQUIPMENT AND FACILITIES

TRANSMITTAL

Final Office Action mailed by the examiner: Sept. 4th, 2003.

Response to the Final Office Action mailed: Nov. 17th, 2003.

Advisory Action mailed by the examiner on Feb. 12th, 2004.

Response to Advisory Action mailed: April 6th, 2004

Petition to Revive Unavoidably Abandoned Application mailed: April 6th, 2004.

Petition to Revive Unintentionally Abandoned Application mailed: June 15th, 2004

Decision to Dismiss Unavoidably Abandoned Application mailed: May 20th, 2004.

Deadline to respond to the May 20th Dismissal: July 20th, 2004.

Examiner: NOLAND, Thomas P.

Legal Instruments Examiner (LIE): Jovana Hayes

Group Art Unit: 2856

06/24/2004 GWORDOF1 00000071 09680286

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665.00 DP

Response on the decision to the Petition to revive an Abandoned Application

Filing date: 10/6/2000

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Date mailed: 6/15/2004
Art Unit: 2856

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Derek L. Woods
Office of Petitions
P.O. Box 1450
Alexandria, VA 22313-1450

TRANSMITTAL

Dear Sir:

Enclosed please find the following documents related to the above-entitled patent application:

1. **Request for Reconsideration of Petition under 37 CFR 1.137**, which begins on page 3 of this paper.
2. **Amendments to the Claims** are reflected in the listing of claims which begins on page 4 of this paper.
3. **Remarks and Conclusions** begin on page 6 of this paper.
4. **Check for \$665.00.** Petition Fee to Revive an Unintentionally abandoned application (37 CFR 1.37 (b))
5. Return Receipt Postcard.

Respectfully submitted,

Eric Paton, Applicant

By: 

Date: 6/14/04

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Eric Paton, Applicant

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CITIZENSHIP: USA

CERTIFICATE OF MAILING

I hereby certify that this paper and the documents attached hereto are being deposited in a postage prepaid, sealed envelope with the United States Postal Service using First Class Mail service under 37 CFR 1.08 on the date indicated and is addressed to "Derek L. Woods, Commissioner for Patents, Alexandria, VA 22313-1450".

Signed:  Date mailed: 6/15/04

Request for Reconsideration of Petition under 37 CFR 1.137

Dear Sir:

Thank you for your continued expedient examination of the present Application. The Decision to DISMISS the Petition to Revive Unavoidably Abandoned Application mailed 5/20/2004 by the Office of Petitions was received by the applicant. The applicant now requests to file a Petition to Revive an Unintentionally Abandoned Application, as recommended by the Petitions Office in their dismissal letter mailed 5/20/04. The entire period of delay was unintentional, including the delay from the date the delay was discovered to the filing of this petition. The applicant includes no showing of unavoidable delay in this petition. The applicant has included the fee for revival after abandonment, totaling \$665.

Respectfully submitted,

Eric Paton, Applicant

By: Eric Paton, Applicant

Date: 
6/14/04

In response to the Advisory Action mailed 2/12/04, please amend the above application as follows:

Proposed Response

AMENDMENT – Claims

This listing of claim(s) will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Cancel claims 18-33

Claims 1-33 (canceled)

Add new claim 34 as follows:

Claim 34 (New) An apparatus for measuring parameters used in manufacturing an integrated circuit or a micromechanical device in microelectronic processing without evasive interruptions to manufacturing equipment, the parameters selected from the group consisting of temperature, liquid and gas flow rate, distance, particles, humidity, pressure, viscosity, radiation, velocity, density, acceleration, stress/strain, pH, and the parameters determined using techniques selected from the group consisting of Energy Dispersive x-ray Spectroscopy (EDS), Cathodoluminescence (CL), X-ray Photoelectron Spectroscopy (*XPS*), Ultraviolet Photoelectron Spectroscopy (UPS), Auger, Electron Spectroscopy (*AES*), Reflection High Energy Electron Diffraction (REELS), X-ray Fluorescence (*XRF*), Photoluminescence (PL), Modulation Spectroscopy, Variable Angle Spectroscopic Ellipsometry (VASE), Fourier Transform Infrared Spectroscopy (FTIR), Raman Spectroscopy, Solid State Nuclear Magnetic Resonance (NMR), Rutherford Backscattering Spectroscopy (RBS), Elastic Recoil Spectroscopy (ERS), Ion Scattering Spectroscopy (ISS), Residual Gas Analyzer (RGA), Dynamic/Static Secondary Ion Mass Spectroscopy, Laser Ionization Mass Spectroscopy (LIMS), Sputtered Neutral Mass

Spectroscopy (SNMS), Glow Discharge Mass Spectroscopy (GDMS), Inductively Coupled Plasma Mass Spectroscopy, Inductively Coupled Plasma Optical Emission Spectroscopy, Neutron Diffraction, Neutron Reflectivity, Neutron Activation Analysis (NAA), Nuclear Reaction Analysis (NRA) and combinations thereof, the apparatus comprising:

one or more sensors, the one or more sensors attached to a surface on the integrated circuit or micromechanical device;

wherein the energy source is a battery functional at temperatures up to 150°C;

wherein the electronic device comprises an analog to digital converter, a signal conditioning device, and a solid state memory device for collecting data;

the apparatus further comprises an external wireless receiving module wherein the collected data is transmitted digitally in real-time from the electronic device to the external wireless receiving module;

the apparatus further comprising an isolation material to protect the electronic device from hostile manufacturing or processing environments;

and wherein the one or more sensors, the electronic device components and the battery are radiation hard.

REMARKS - General

Applicant is grateful for the examiner's suggested amendments to the claims. Applicant accepts all suggested amendments by the examiner. Applicant has CANCELED claims 18-33, and has added NEW ALLOWABLE claim 34 as recommended by the examiner. No other changes are made to the new claim, except those recommended by the examiner. Applicant requests authorization to correct obvious minor informalities by the examiner's amendment.

CONCLUSIONS

Applicant respectfully submits that for all the foregoing reasons, the claimed subject matter describes patentable invention. Furthermore, Applicant submits that the specification is adequate and that the claims are in a condition for allowance. No new matter has been entered.

Respectfully submitted,

Eric Paton, Applicant

By: 

Date: 6/14/04

Eric Paton, Applicant

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